Special Issue

Innovative Remote Sensing Technologies in Precision Agriculture

Message from the Guest Editors

This Special Issue welcomes papers on advances in remote sensing for precision agriculture. Topics include, but are not limited to, biochemical and biophysical parameter estimation, soil condition monitoring, yield estimation, pest and disease forecasting, artificial intelligence, novel proximal sensors, and the recent application of multispectral, hyperspectral, LiDAR, SAR, and thermal remote sensing in crop monitoring. Keywords

- artificial intelligence algorithms
- yield estimation
- biochemical and biophysical parameters estimation
- soil condition monitoring
- vegetation remote sensing product validation
- commercial crops, grass, and other crops

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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